

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE



Applicants: Patrick T. Petruno, Daniel B. Roitman, Rong Zhou, Robert E. Wilson
and Ye Chen
Assignee: Agilent Technologies, Inc.
Title: OPTOELECTRONIC RAPID DIAGNOSTIC TEST SYSTEM
Serial No.: 10/816,636 Filing Date: April 1, 2004
Examiner: Melanie J. Yu Group Art Unit: 1641
Docket No.: 10040213-1

San Jose, California
March 24, 2006

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**RESPONSE TO FINAL OFFICE ACTION
SUBMITTED WITH REQUEST FOR CONTINUED EXAMINATION (RCE)**

Dear Sir:

This response to the Final Office Action dated January 24, 2006, which has a
statutorily shortened period for response that ends April 24, 2006, includes:

A listing of the claims presented for further examination; and
Remarks offered in reply to the Final Office Action; and is accompanied by
A Request for Continued Examination.

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